

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/565,537	MELKONIAN ET AL.	
Examiner	Art Unit	
Taeyoon Kim	1651	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST search (USPG- pub;USPAT;USOCR;EPO;JPO;Derwe nt)	4/26/2007	тк		
Inventor search (PALM)	4/27/2007	тк		
updated search	10/18/2007	тк		
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